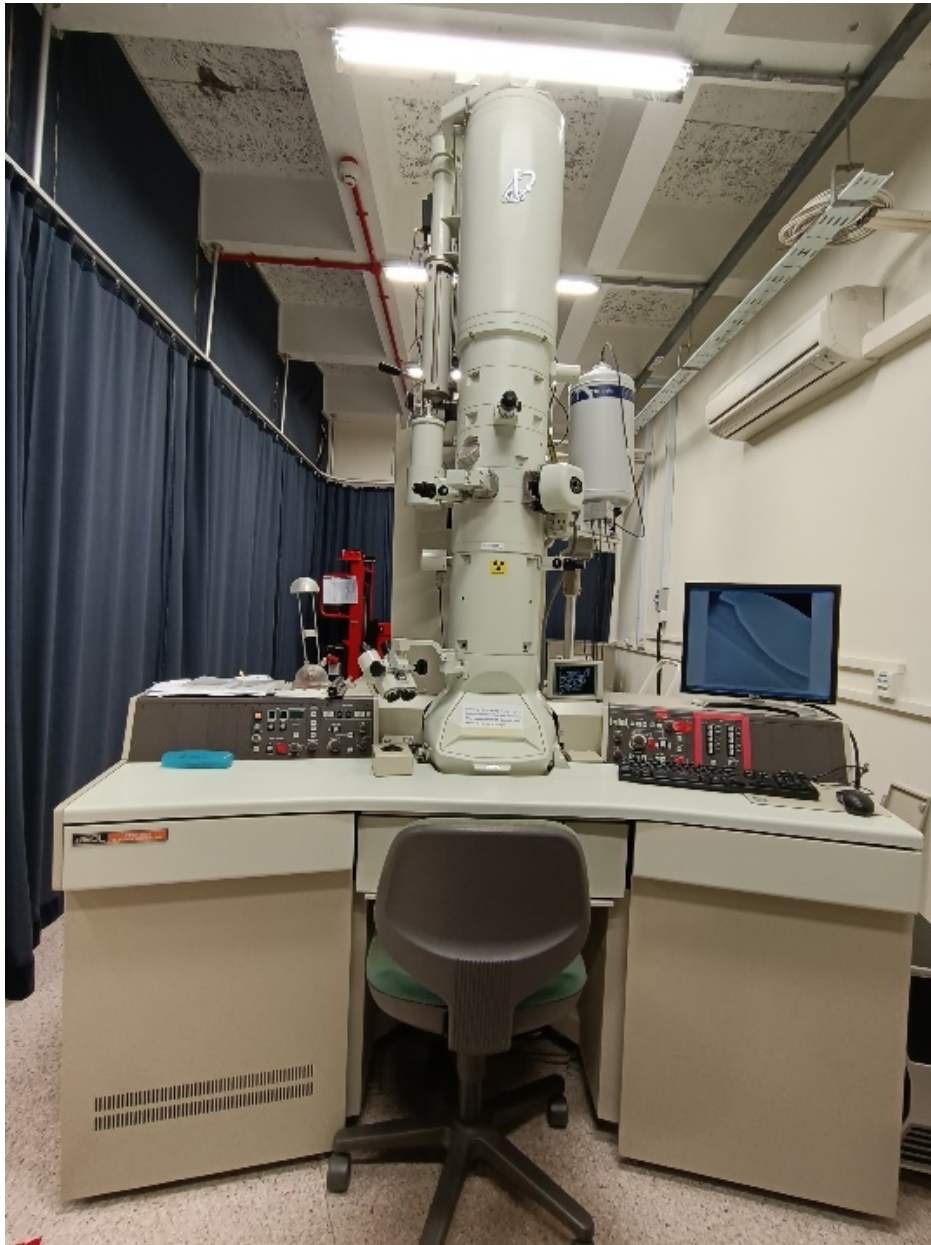


JEOL JEM-3010 Electron Microscope



The JEM-3010 Electron Microscope, a 300KV ultrahigh resolution analytical TEM (transmission electron microscope), has been born out of the ultrahigh resolution, micro-area analysis, electron diffraction, and convergent beam electron diffraction techniques.

This UHR (ultrahigh resolution) type JEM-3010 provides a theoretical resolution of 0.17nm and a microprobe diameter of 1.0nm in diameter allowing the ultra-micro-area X-ray analysis, ultra-microarea electron diffraction, and convergent beam electron diffraction to be carried out while directly observing structure images which show atomic arrays.

This microscope is also equipped with Oxford energy dispersive X-ray spectroscopy allowing microarea element analysis.